A Comparative Cost/Security Analysis of Fault Attack Countermeasures

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Outline

- Introduction
- Error detection codes
- Repetition/duplication
- Conclusion

Introduction

- Countermeasures against fault attacks
 - -HW, SW
 - Active, passive
- Examples:
 - Bus encryption, sensors, randomizations, ...
 - Error detection techniques
- ⇒ Comparative analysis (block ciphers)





Error detection techniques using space redundancies

• Block cipher without protection:







A first proposal





e.g. [Karri et al. 2003]





A first proposal

- Mainly costs an additional Boolean function for the substitution box
- Any modification of the parity will be detected at the round's output
- >< Faults of even order will *not* be detected
 - OK for integrated circuits
 - probably not for malicious adversaries





A first proposal

<u>Fact 1</u>: Probability of errors in integrated circuits 1-bit: 85%, 2-bit: 10%, 3-bit: 3%, 4-bit: 1% [Moshanin et al. 98]

Fact 2: Numbers of faults required to defeat, *e.g.* the AES Rijndael: 2 [Piret *et al.* 04]

Fact 3: Malicious adversaries: possibly enhanced with space and time localization





Possible improvements

- Weaknesses of the first proposal:
 - Only one parity bit is used
 - Parity codes are linear
 - (Only one checker per round)

Multiple bit parity codes

- *e.g.* [Bertoni *et al.* 03]: one parity bit per byte for the AES Rijndael
- HW penalty: the parities are now affected by the diffusion layer
- Security improvement:
 P[double faults affecting the same byte]~12%





Non-linear robust codes #1

- [Karpovsky et al. 04]:
 - non-linear code for the S-box
 - check only a few bits
 - linear code for the rest:
 - (8-bit parity code per column):











Non-linear robust codes #2

• [Karpovsky et al. 04]:

Addition of cubic networks to the previous linear scheme:





HW cost of the different solutions

• Based on the original author's estimations

Method	Sin. fault	Mul. fault	Area	Delay	Thr.	Thr./Area
	detection	detection	overhead	overhead	overhead	overhead
single	yes	no	+7.4%	+6.4%	-	-
parity bit						
multiple	yes	double faults	+20%	-	-	-
parity bits		masked with				
(n = 16)		$P \propto \frac{2}{n+1}$				
linear +	weak	good	$+35\%^{*}$	-	-	-
non-linear						
codes						
non-linear	good,	good,	+77%	+15%	-13%	-51%
r-bit codes	missed with	missed with				
(r = 28)	$P \propto 2^{-2r}$	$P \propto 2^{-2r}$				



Observations

- In general, the HW overhead increases with the fault detection capabilities
- The overhead obviously depends on the cost of the original primitive (because estimated in %)
- \Rightarrow Security vs. efficiency tradeoff





Other proposals

• Concurrent error detection for involution ciphers







Other proposals

- What is the real cost of the proposal?
- A similar proposal would be:



 \Rightarrow Repetition code

- \Rightarrow Throughput divided by 2
- \Rightarrow No permanent faults detected





Feedback modes?

• Pipeline cannot be used for efficiency... ... but can be used for fault detection







Feedback modes?

 $\Rightarrow \text{There exist contexts where fault detection} \\ \text{can be obtained "for free"} \\ \text{Similar example:} \\ [Karri et al. 2002] \\ (repetition/duplication) \\ \end{cases}$

ciphertext



decrypt round 1

Conclusions

S. Mitra, E.J. McCluskey, "Which Concurrent Error Detection Scheme to Choose?", International Test Conference 2000

⇒ Most efficient concurrent error detection schemes exceed the cost of duplication



• When can this be improved?

Theoretically two possibilities:

- restrict the fault model (e.g. multiplicities)
- detect with lower probabilities

Both solutions are not convenient for crypto





- Or practically... in certain specific contexts:
 - Encryption in feedback modes
 - Encryption/decryption available



 \Rightarrow Purely theoretical solutions (*e.g.* algorithmic tamper proofness) are probably not completely unrealistic

? Efficiency improvements of non-linear robust codes



